

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Florida Calibration Lab 3408 W. 84 #109, Hialeah, FL 33018

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2017

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Dimensional, Electrical, Mass, Force & Weighing Devices Calibration (As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Sussen

Tracy Szerszen President

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084

Initial Accreditation Date: January 24, 2014 Accreditation No.:

October 03, 2022

Issue Date:

Expiration Date: January 31, 2025

78127

Certificate No.: L22-654

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: www.pjlabs.com



Certificate of Accreditation: Supplement

Florida Calibration Lab

3408 W 84 Street # 109, Hialeah, FL. 33018 Contact Name: Yami Sanchez Phone: 305-421-7212

Accreditation is granted to the facility to perform the following calibrations:

Dimensional

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Calipers ^F	0.05 in to 24 in	(315 + 7.9L) µin	Gage Blocks
Inside Micrometers F	1.5 in to 12 in	(13.8 + 12L) µin	Long Gage Blocks FCP-100
Outside Micrometers ^F	0.05 in to 12 in	$(30 + 4L) \mu in$	FCP-100 FCP-101
Dial Indicator ^F	0.001 to 2 in	(360 + 18L) µin	
Depth Micrometer ^F	0.05 in to 12 in	$(51.2 + 6L) \mu in$	

Electrical

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED		
Equipment to Output DC Voltage ^F	100 mV	0.034 mV	Agilent 34401A FCP-152		
	1 V	0.027 mV			
	10 V	1.2 mV			
	100 V	17 mV			
	1 000 V	0.22 V			
Equipment to Output AC Voltage (At the listed from					
3 Hz to 5 Hz	100 mV	1.7 mV			
5 Hz to 10 Hz	100 mV	0.78 mV			
10 Hz to 20 kHz	100 mV	0.2 mV			
20 kHz to 50 kHz	100 mV	0.28 mV			
50 kHz to 100 kHz	100 mV	1.4 mV			
100 kHz to 300 kHz	100 mV	9 mV			
Equipment to Output AC Voltage (At the listed frequencies) ^F					
3 Hz to 5 Hz	1 V to 750 V	0.6 % of Reading + 0.45 V	Agilent 34401A FCP-152		
5 Hz to 10 Hz	1 V to 750 V	0.7 % of Reading + 0.45 V			
10 Hz to 20 kHz	1 V to 750 V	0.12 % of Reading + 0.45 V			
20 kHz to 50 kHz	1 V to 750 V	0.18 % of Reading + 0.6 V			
50 kHz to 100 kHz	1 V to 750 V	1.2% of Reading + 1.2 V			
100 kHz to 300 kHz	1 V to 750 V	8 % of Reading + 7.5 V			



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Electrical			
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Equipment to Output Resistance ^F	100 Ω	0.023 Ω	Agilent 34401A FCP-152
	1 kΩ	0.17 Ω	
	10 kΩ	1.7 Ω	
	100 kΩ	17 Ω	
	1 MΩ	0.17 kΩ	
	10 MΩ	6.2 kΩ	
	100 MΩ	1.2 ΜΩ	
Equipment to Output DC	10 mA	0.003 6 mA	
Current ^F	100 mA	0.066 mA	
	1 A	0.001 3 A	
	3 A	0.005 A	
Equipment to Output AC Voltage (At the listed fi	requencies) ^F	97	
3 Hz to 5 Hz	0.001 A to 1 A	1 % of Reading + 0.000 4 A	
5 Hz to 10 Hz	0.001 A to 1 A	0.3 % of Reading + 0.000 4 A	
10 Hz to 5 kHz	0.001 A to 1 A	0.1 % of Reading + 0.000 4 A	
Equipment to Output AC Voltage (At the listed fi	requencies) ^F		
3 Hz to 5 Hz	1 A to 3 A	1.1 % of Reading + 0.001 8 A	
5 Hz to 10 Hz	1 A to 3 A	0.35 % of Reading + 0.001 8 A	-
10 Hz to 5 kHz	1 A to 3 A	0.15 % of Reading + 0.001 8 A	
Equipment to Measure Free (At the listed voltages) ^F			
3 Hz to 5 Hz	100 mV to 750 V	0.15 % of Reading	
5 Hz to 10 Hz	100 mV to 750 V	0.1 % of Reading]
10 Hz to 40 Hz	100 mV to 750 V	0.1 % of Reading	
40 Hz to 300 kHz	100 mV to 750 V	0.05 % of Reading]



(OIML)

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MEASURED INSTRUMENT, RANGE OR NOMINAL CALIBRATION AND CALIBRATION QUANTITY OR GAUGE DEVICE SIZE AS MEASUREMENT EQUIPMENT APPROPRIATE CAPABILITY EXPRESSED AND REFERENCE AS AN UNCERTAINTY (±) STANDARDS USED Scale Class I FO $(1.94 \text{ x} 10^{-5} \text{ Wt} + 2.98 \text{ x} 10^{-2}) \text{ g}$ 0.001 g to 200 g Class F1 (OIML) (OIML) Scale class II FO 0.003 kg to 10 kg $(2.46 \text{ x } 10^{-6} \text{ Wt} + 8 \text{ x } 10^{-5}) \text{ g}$ FCP-105 (OIML) Scale class III FO $(9.8 \times 10^{-6} \text{ Wt} + 8.8 \times 10^{-2}) \text{ g}$ 0.001 kg to 10 kg

Mass, Force, and Weighing Devices

- 1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
- 2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
- 3. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location. Example: Outside Micrometer ^F would mean that the laboratory performs this calibration at its fixed location.
- 4. The presence of a superscript FO means that the laboratory performs calibration of the indicated parameter both at its fixed location and onsite at customer locations. Example: Outside Micrometer^{FO} would mean that the laboratory performs this calibration at its fixed location and onsite at customer locations.
- 5. Measurement uncertainties obtained for calibrations performed at customer sites can be expected to be larger than the measurement uncertainties obtained at the laboratories fixed location for similar calibrations. This is due to the effects of transportation of the standards and equipment and upon environmental conditions at the customer site which are typically not controlled as closely as at the laboratories fixed location.
- 6. The term L represents length in inches or millimeters as appropriate to the uncertainty statement.
- 7. The term Wt represents weight in pounds or grams (including SI multiple and submultiple units) appropriate to the uncertainty statement.